

Precision Timing with Low Gain Avalanche Detectors in the CMS MTD Endcap Timing Layer

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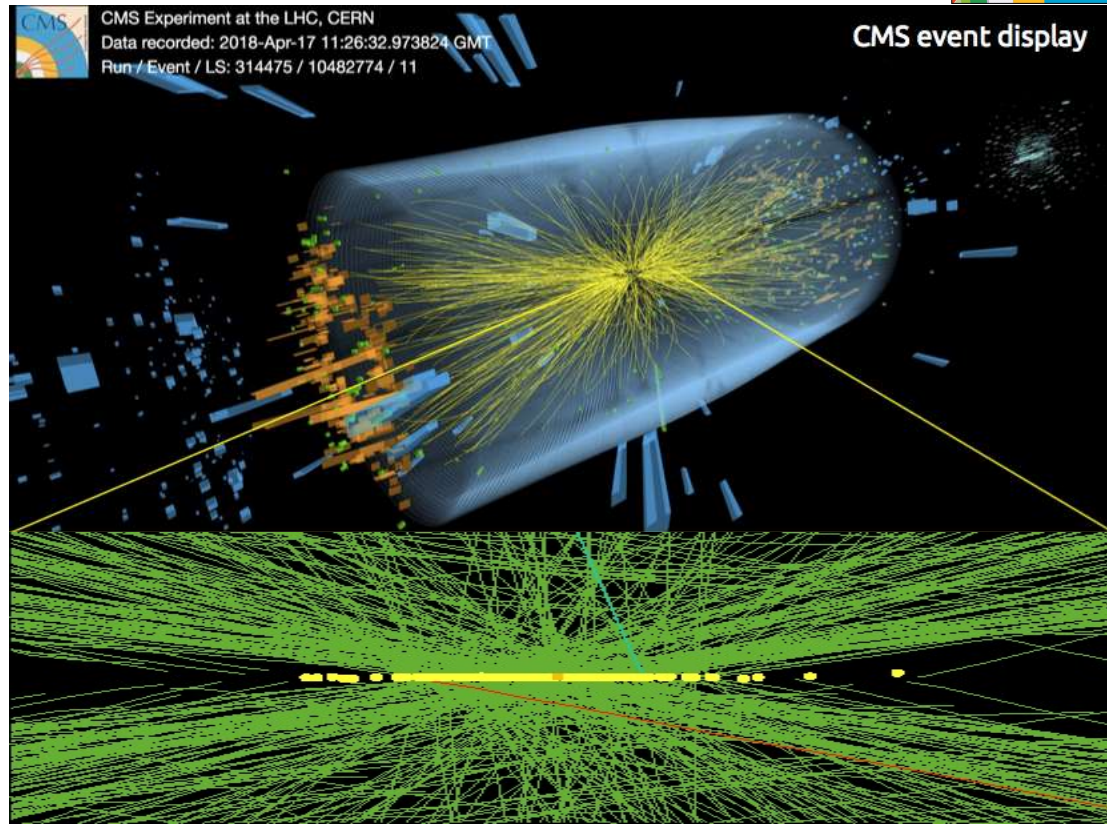
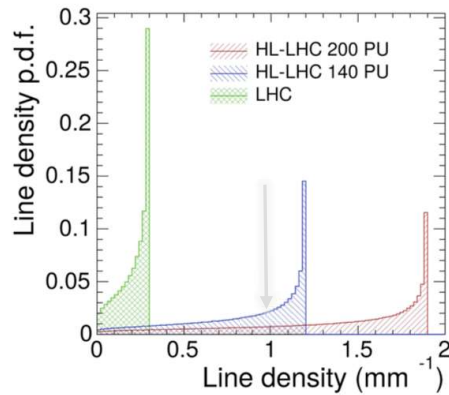
On behalf of CMS Collaboration

The High-Lumi LHC challenge



	Inst. Lumi (cm ⁻² s ⁻¹)	Peak pileup (PU)
LHC	1.7 x 10 ³⁴	60
HL-LHC	5-7.5 x 10 ³⁴	140-200

Up to **5x higher vertex density**
Track-vertex compatibility cut
 is @ 1mm



At HL-LHC: without extra info on the track 15-20% luminosity loss

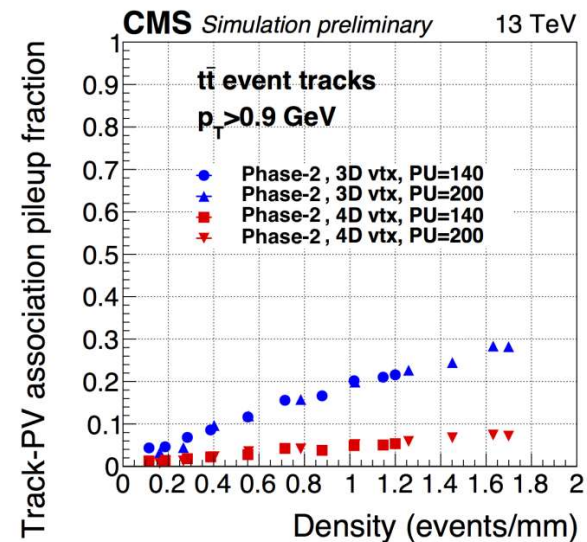
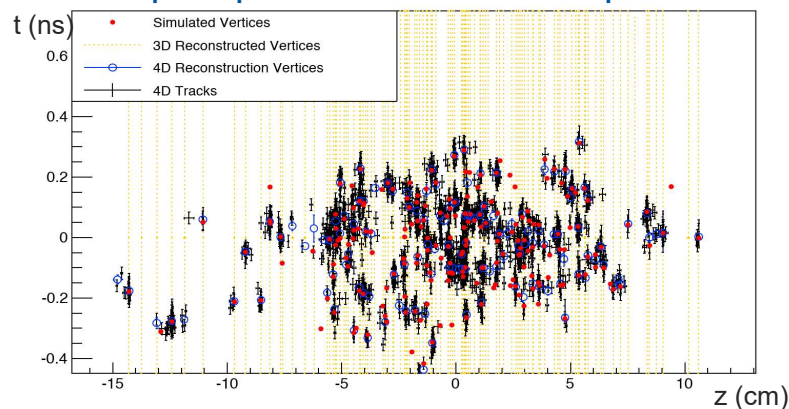
Timing resolution requirements



HL-LHC:

- According to CMS simulations:
- $\langle t_{\text{vertex}} \rangle_{\text{RMS}} = 153 \text{ ps}$
- Average distance between two vertexes: **500 μm**
- Fraction of overlapping vertexes: **15-20%**
- Of those events, a large fraction will have significant degradation of the quality of reconstruction

200 pileup interactions in 4D space



With **30ps time resolution**, instances of vertex merging are reduced from 15% in space to 1% in space-time

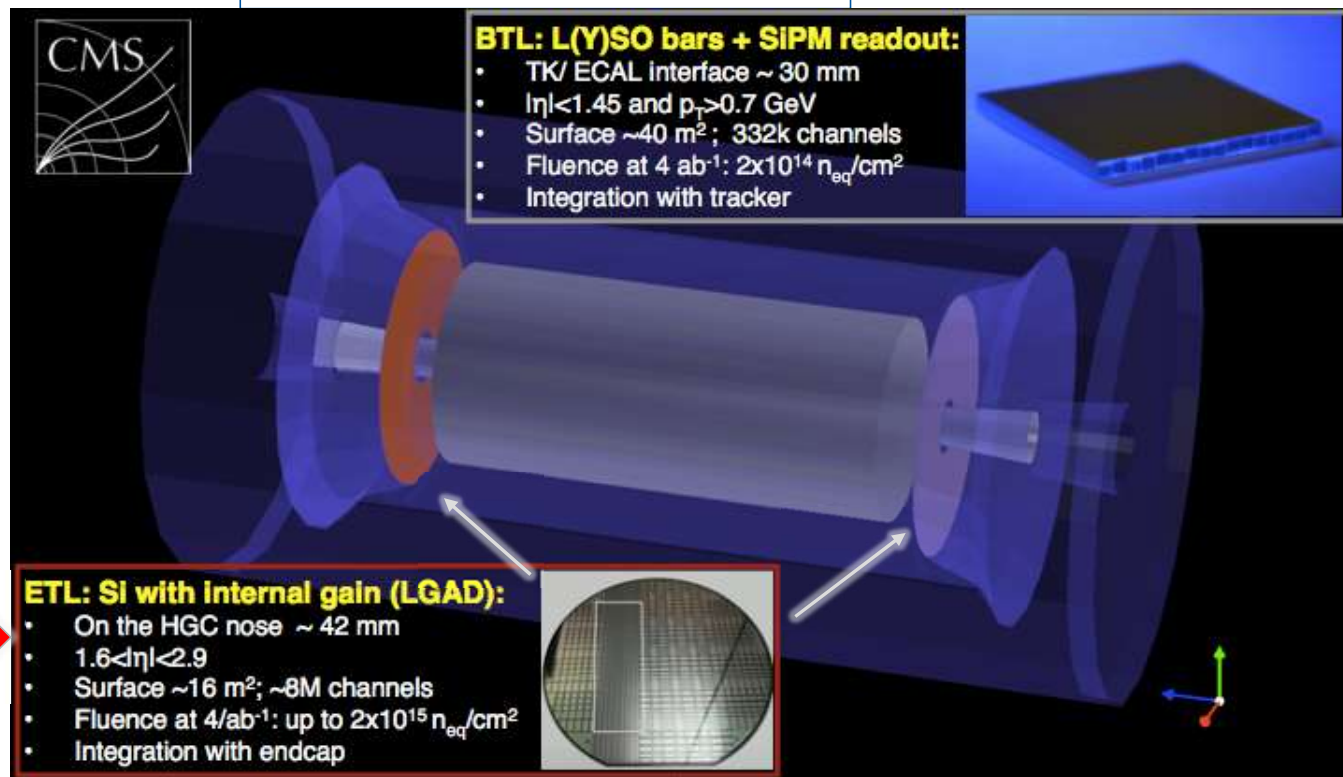
Mip Timing Detector in CMS to consolidate particle flow performance at 140PU events, and extend it to 200PU

CMS MIP Timing Detector



A precise timing detector can be used for Particle Identification or for pile-up suppression

30-40 ps timestamp for every track



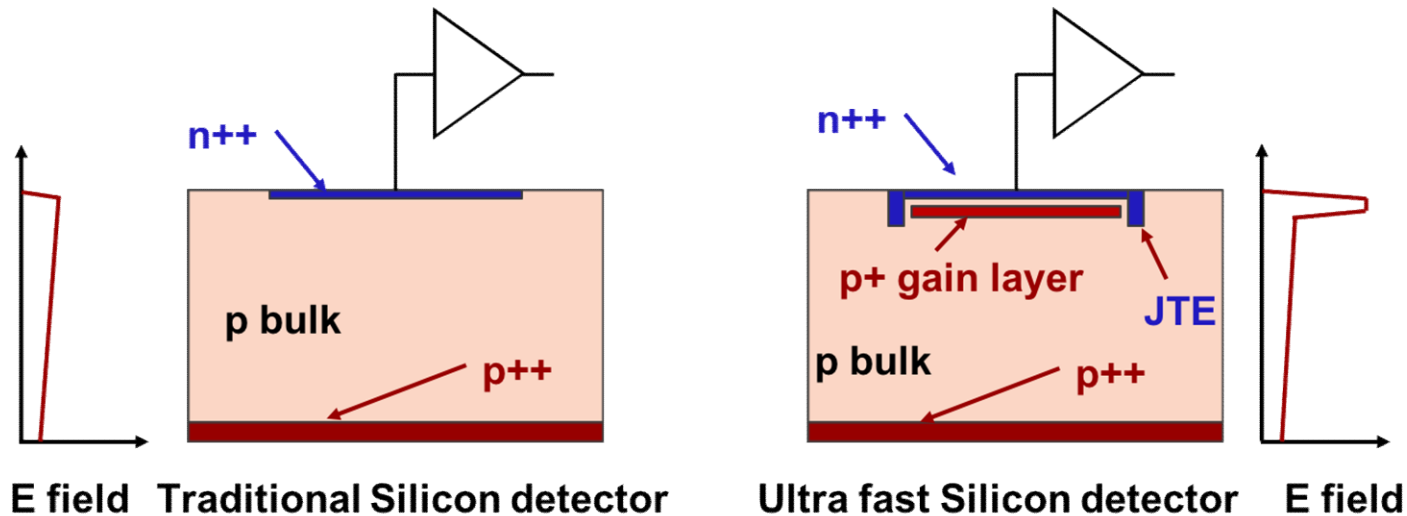
Endcap
Timing
Layer

MTD TDR Fully Approved https://twiki.cern.ch/twiki/pub/CMS/MTDTechnicalDesignReport/MTD_TDR_final_20191002.pdf

ETL instrumented with Ultra Fast Silicon Detectors



Ultra Fast Silicon Detectors (UFSDs) are Low Gain Avalanche Diodes (LGADs) optimized for timing employing a thin multiplication layer to increase the output signal at the passage of a particle of a factor $\sim 10 - 20$



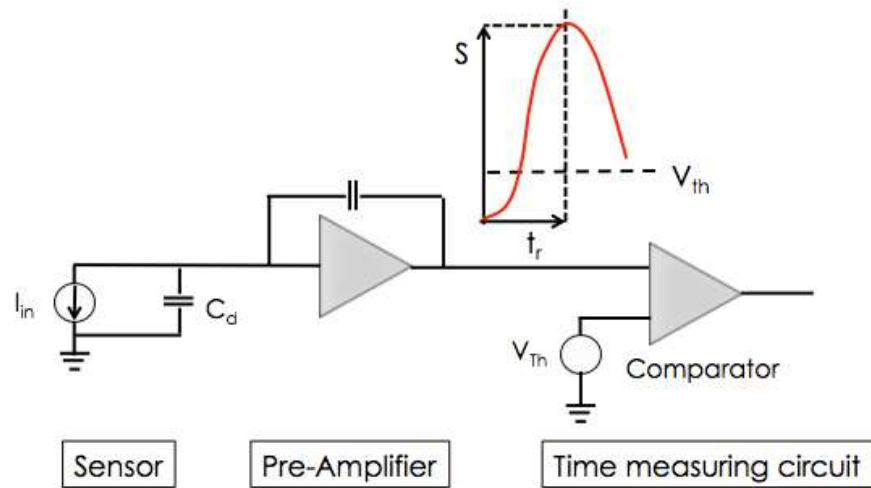
The low-gain mechanism, obtained with a moderately doped p-implant, is the defining feature of the design.

The low gain allows segmenting and keeping the shot noise below the electronic noise, since the leakage current is low.

Silicon time-tagging detector



(a simplified view)



Time is set when the signal crosses the comparator threshold

The timing capabilities are determined by the characteristics of the signal at the output of the pre-Amplifier and by the TDC binning.

Strong interplay between sensor and electronics

Good time resolution needs very uniform signals



Signal shape is determined by Ramo's Theorem:

$$i \propto qvE_w$$

Drift velocity

Weighting field

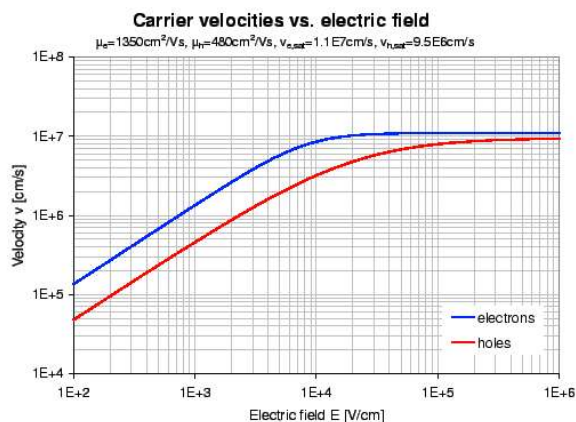
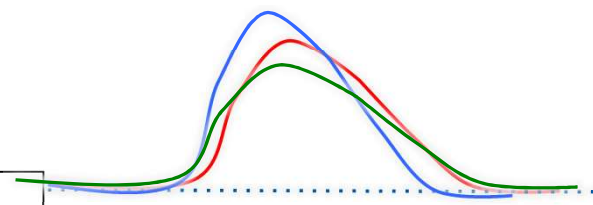
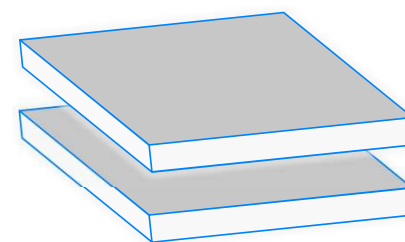


Figure: Electron and hole velocities vs. the electric field strength in silicon.

The key to good timing is the uniformity of signals:
 Drift velocity and Weighting field need to be as uniform as possible
Basic rule: parallel plate geometry



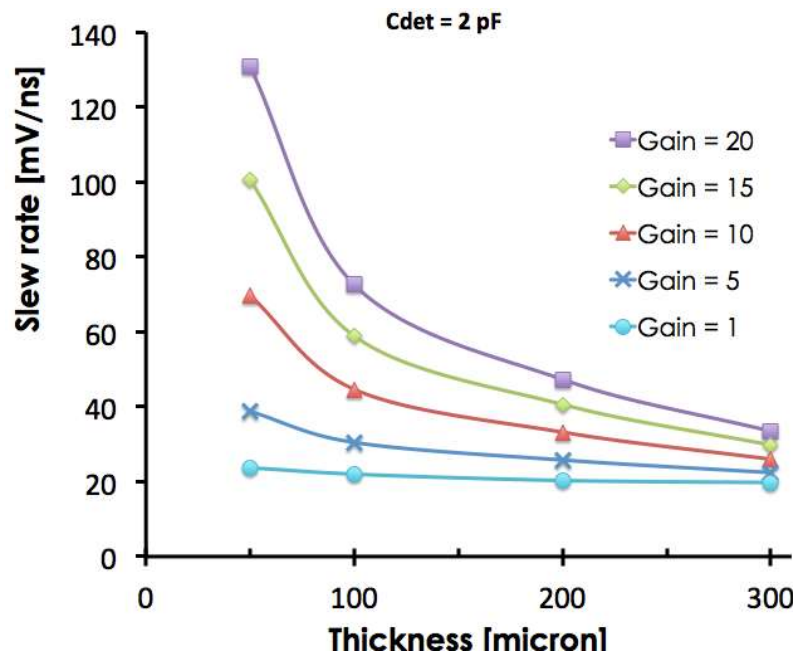


Gain current vs Initial current

$$\frac{di_{gain}}{i} \propto \frac{dN_{Gain} q v_{sat} \frac{k}{d}}{k q v_{sat}} = \frac{75(v_{sat} dt) G q v_{sat} \frac{k}{d}}{k q v_{sat}} \propto \frac{G}{d} dt$$



→ Go thin!!



(Real life is a bit more complicated, but the conclusions are the same)

Full simulation

(assuming 2 pF detector capacitance)

300 micron:

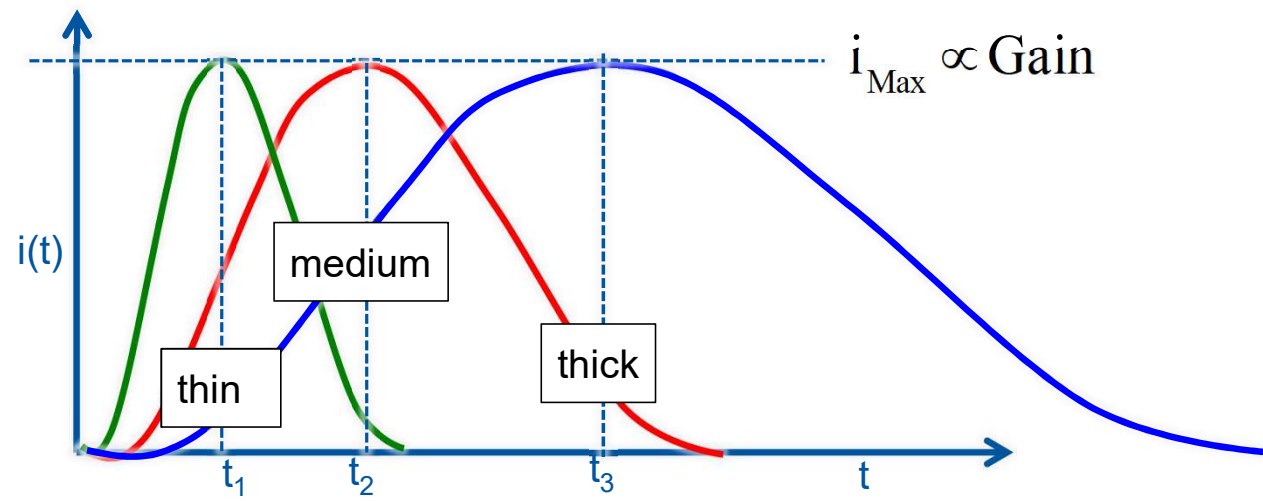
~ 2-3 improvement with gain = 20

Significant improvements in time resolution require **thin** detectors



Gain and Signal current

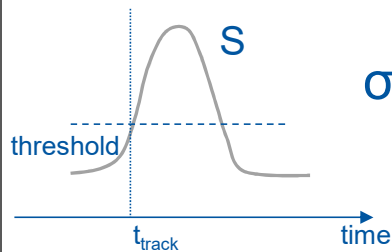
$$\frac{dV}{dt} \propto \frac{G}{d}$$



The rise time depends only on the sensor thickness $\sim 1/d$



Time resolution

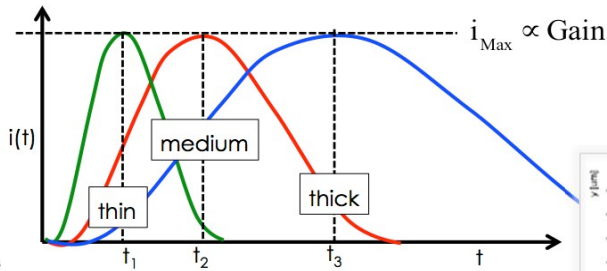


$$\sigma_t^2 = \sigma_{\text{Jitter}}^2 + \sigma_{\text{Time Walk}}^2 + \sigma_{\text{Landau Noise}}^2 + \sigma_{\text{Distortion}}^2 + \sigma_{\text{TDC}}^2$$

Negligible
Optimize FE electronics

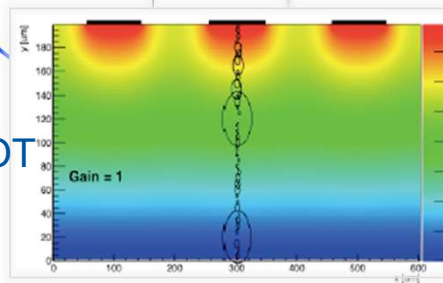
Negligible
Optimize RO electronics

$\sigma_{\text{Jitter}} \approx N / (dV/dt) \approx t_{\text{rise}} / (S/N)$
 → needs **Gain** to increase S/N
 → needs **thin detector** to decrease t_{rise}



$I_{\text{Ramo}} \approx q v_{\text{drift}} E_w$
 Requires **uniform** v_{drift} and E_w
 ↓
 parallel plate geometry
 strip implant ~ pitch

NB: signal amplitude **DOES NOT** depend on detector thickness

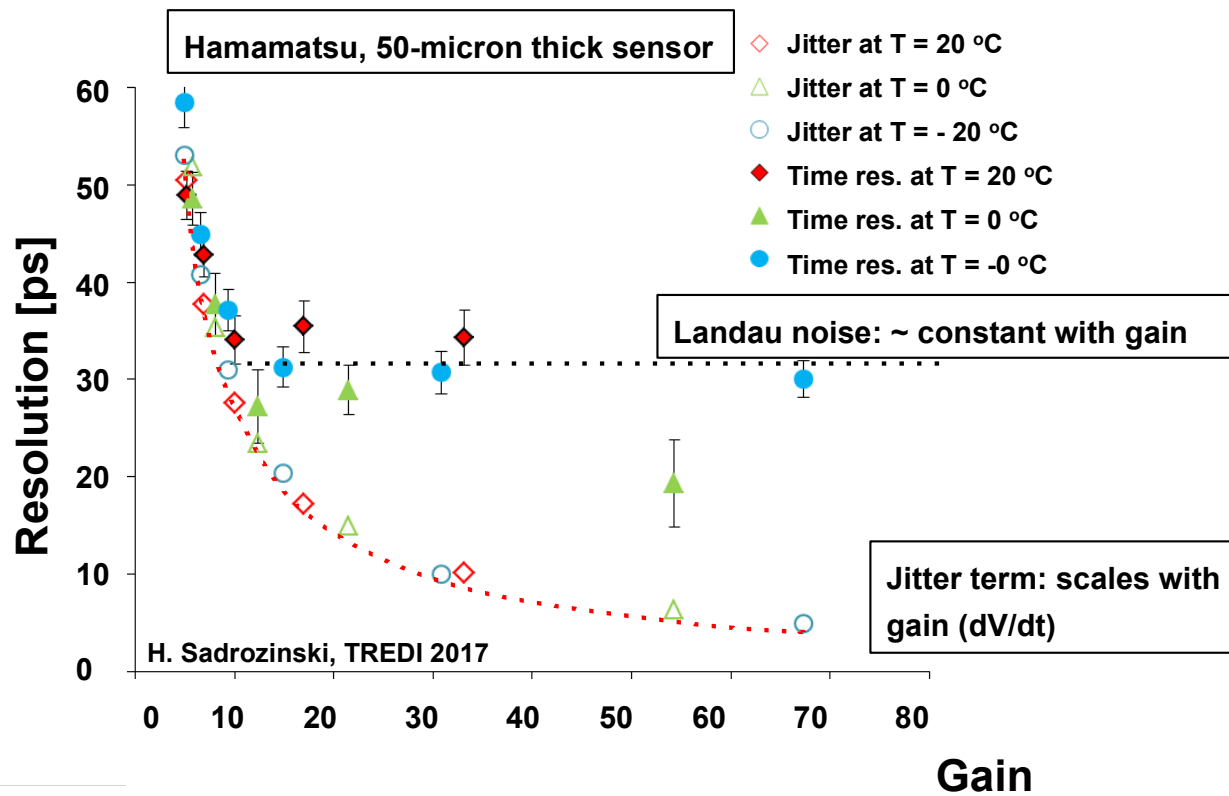


Decreases with detector thickness
 Intrinsic Limit $\sigma_{\text{Landau Noise}} \approx 25\text{ps}$



UFSD time resolution

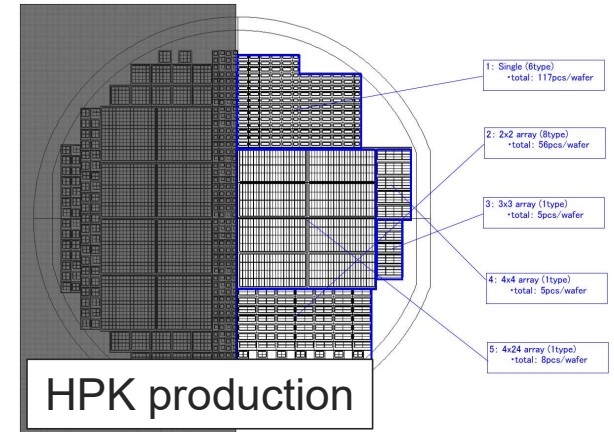
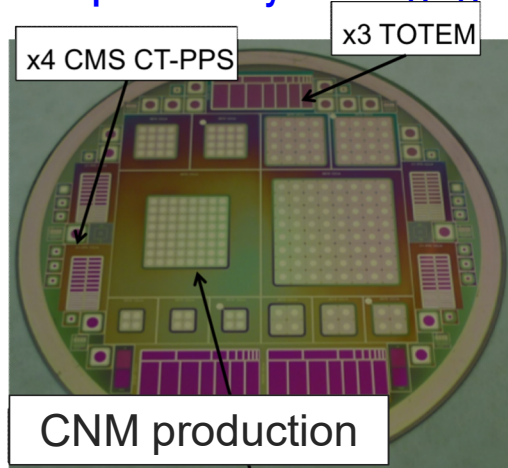
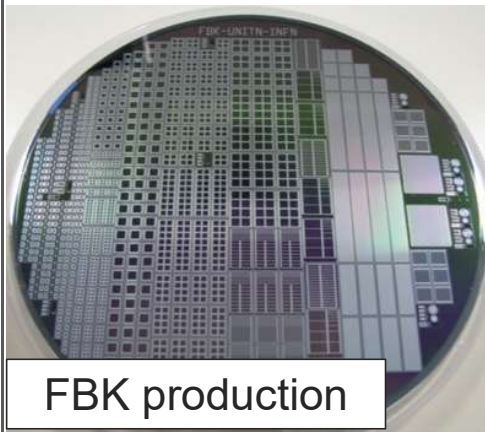
UFSD from Hamamatsu: 30 ps time resolution,



Foundries Producing LGADs for the MTD



Using LGADs for a “CMS size” detector poses many challenges: 3 sensor producers considered



Producers have different approaches for radiation damage mitigation, but all vendors can fulfil the CMS requirements, including a factor of 2 safety margin

CMS1 delivered in Q3 2018

Next production: Q4 2019/Q1 2020

CMS1 production is due to arrive in Q4

2019 /Q1 2020

Next production: Q4 2019/Q1 2020

- Q3 2021: Sensor vendor qualification and final geometry selection
- Q3 2022: Sensor vendor selection and pre-production start

ON SCHEDULE



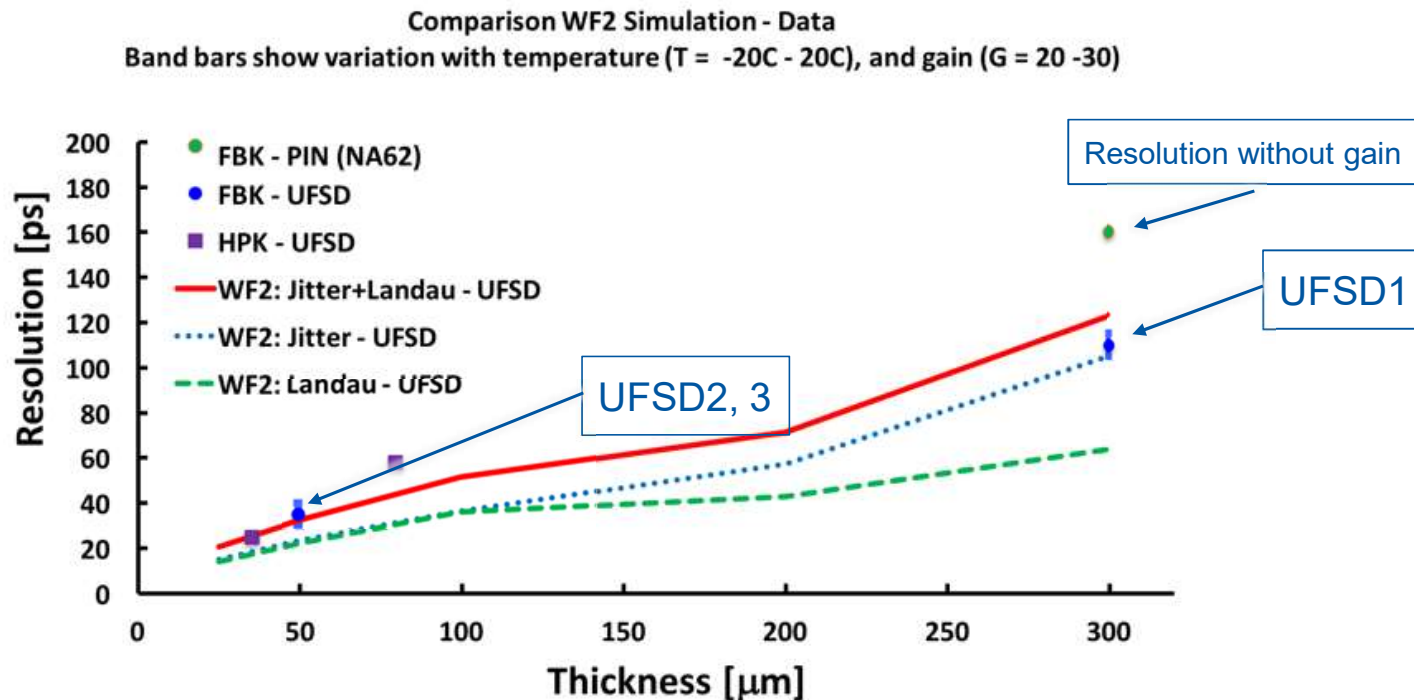
UFSD time resolution summary

The UFSD advances via a series of productions.

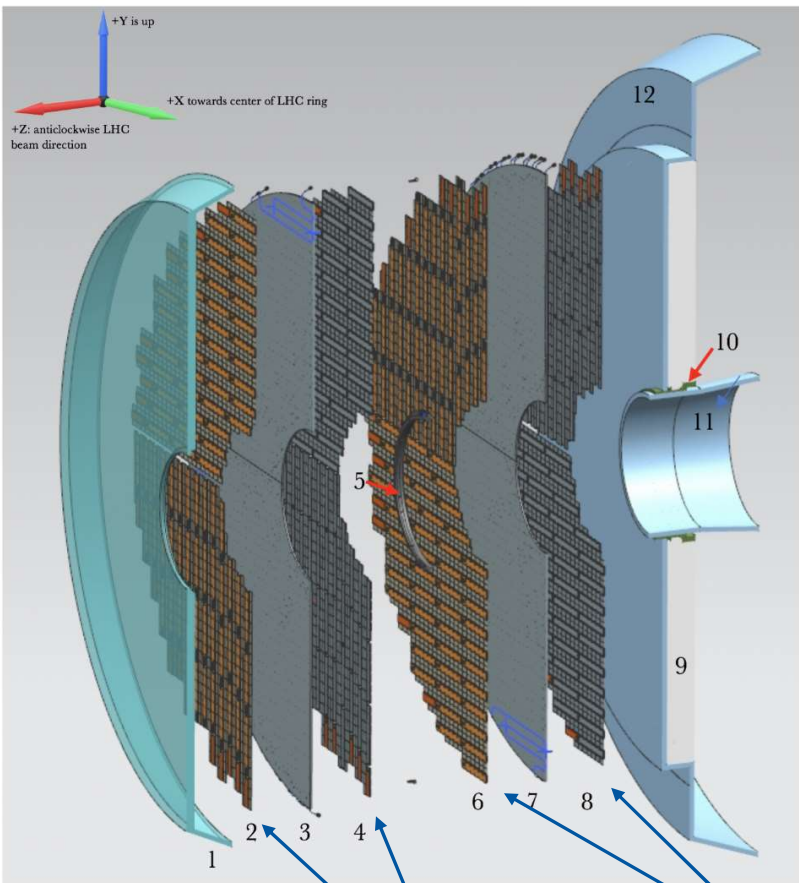
For each thickness, the goal is to obtain the intrinsic time resolution

Achieved:

- 20 ps for 35 micron
- 30 ps for 50 micron



ETL Structure

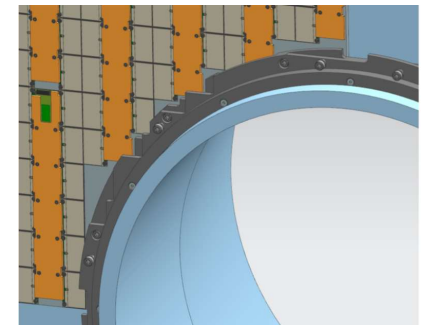
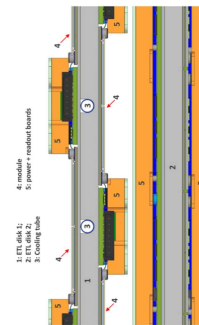


Two disks of UFSDs (per side) $1.6 < |\eta| < 2.9$:

Average 1.8 hits per track

Designed for $\sigma < 50$ ps per hit

- 1: ETL Thermal Screen
- 2: Disk 1, Face 1
- 3: Disk 1 Support Plate
- 4: Disk 1, Face 2
- 5: ETL Mounting Bracket
- 6: Disk 2, Face 1
- 7: Disk 2 Support Plate
- 8: Disk 2, Face 2
- 9: HGCal Neutron Moderator
- 10: ETL Support Cone
- 11: Support cone insulation
- 12: HGCal Thermal Screen



Sensors are mounted in rows on each face of Aluminum cooling disks, staggered wrt opposite face to host readout boards without losing coverage

Disk 1: 2 faces

Disk 2: 2 faces

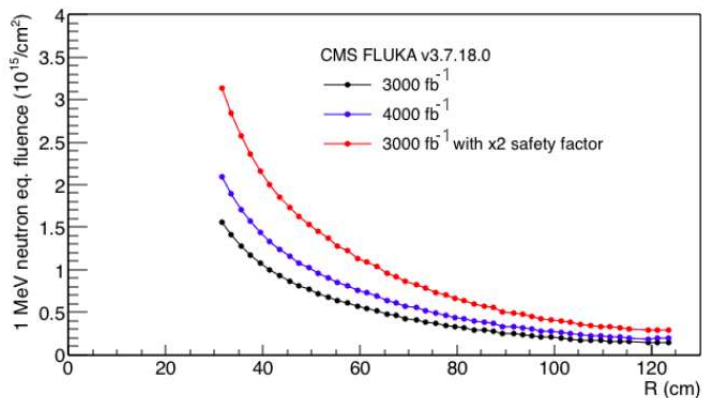
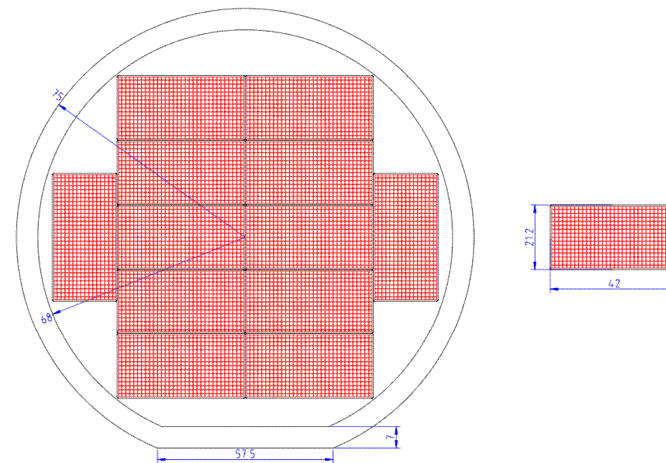
UFSDs for the ETL



Using UFSDs for a “CMS size” detector poses many challenging

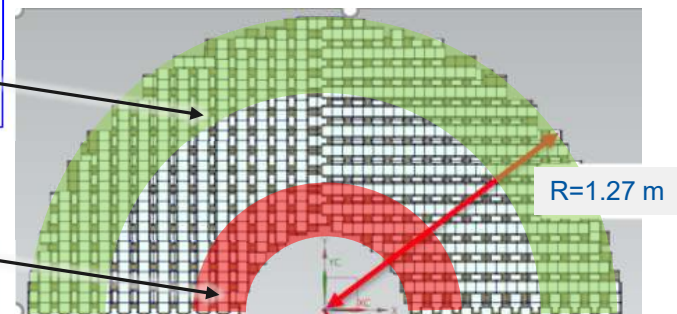
Sensor specifications:

- **Intrinsic Gain: 10-20**
- **Pad size: 1.3 x 1.3 mm²**
- **High fill factor (>85% per layer)**
- **2-disk x-y layout**
- **Number of sensors: ~18000 (~ 16 m², ~2k 6-inch wafers)**
- **Sensors of 2x4 cm²**
- **Radiation hardness**



Less than 4x10¹⁴ n_{eq}/cm² for 50% of sensors

Up to 2x10¹⁵ n_{eq}/cm² for 15% of sensors



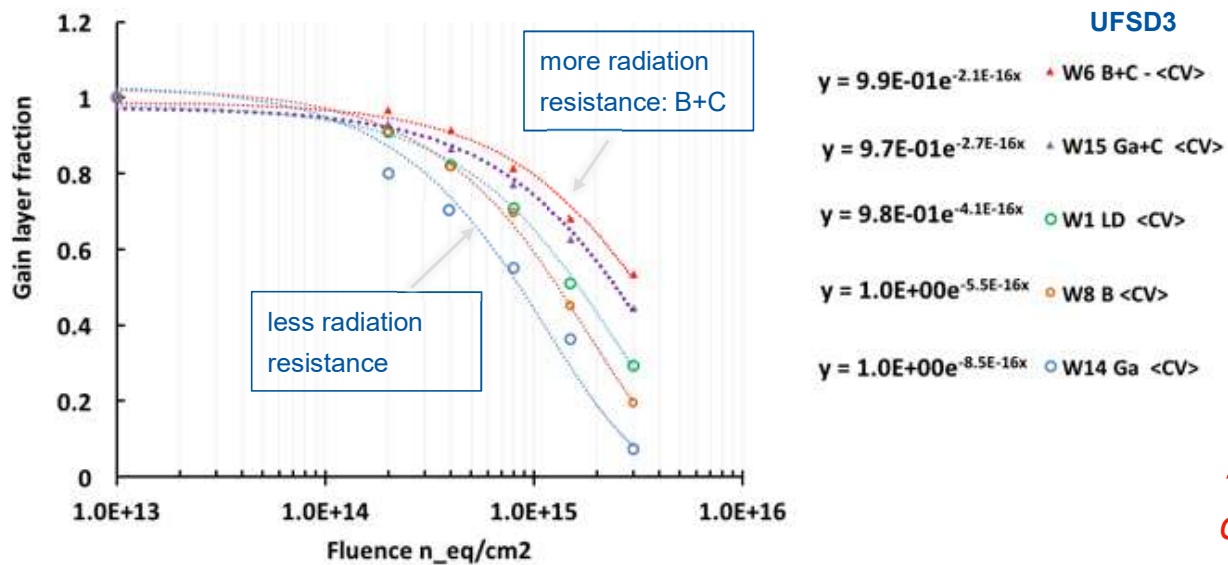
Irradiation effects



Irradiation causes 3 main effects:

- Decrease of charge collection efficiency due to trapping
- **Doping creation/removal (the Gain fades)**
- Increased leakage current, shot noise

But...

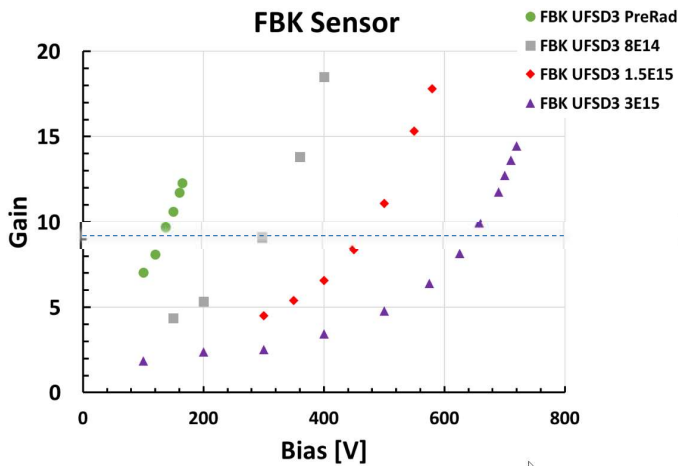
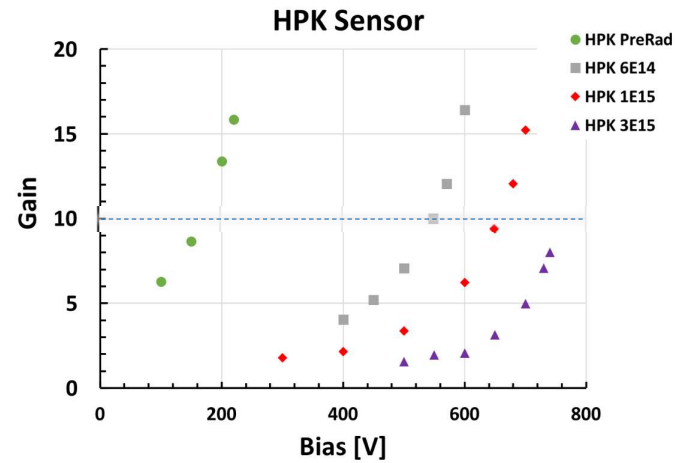
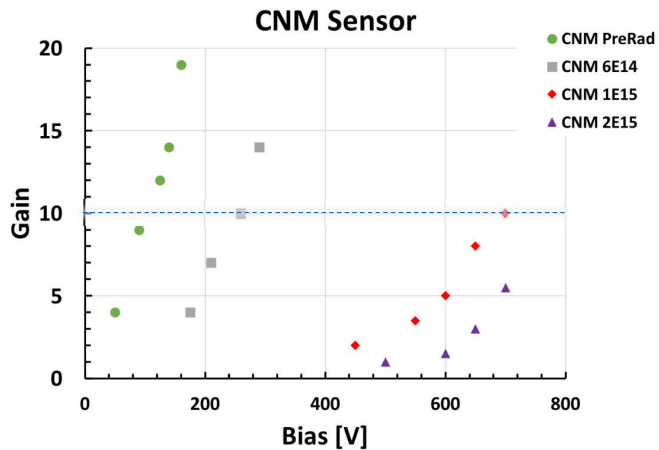


Carbon addition works really well, increasing by a factor of 2-3 the radiation hardness

→ more details in Marco Ferrero contribution in poster session



Vendors performances...so far



- All vendors successful in delivering **G = 10** till the end of HL-LHC
- CNM HPK similar behavior, while
- FBK, can reach $G = 10$ at lower Bias



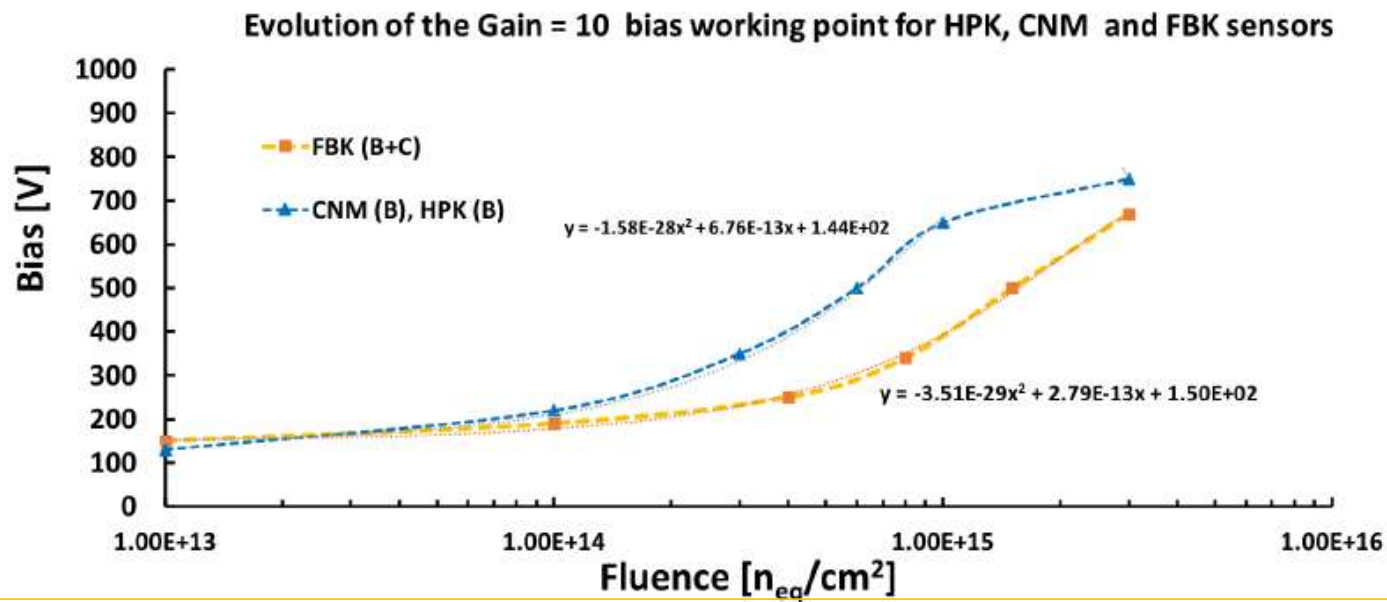
Refs:

<https://arxiv.org/abs/1804.05449v2>,

<https://arxiv.org/abs/1707.04961>,

<https://doi.org/10.1016/j.nima.2018.08.040>

On the detector sensor biasing scheme



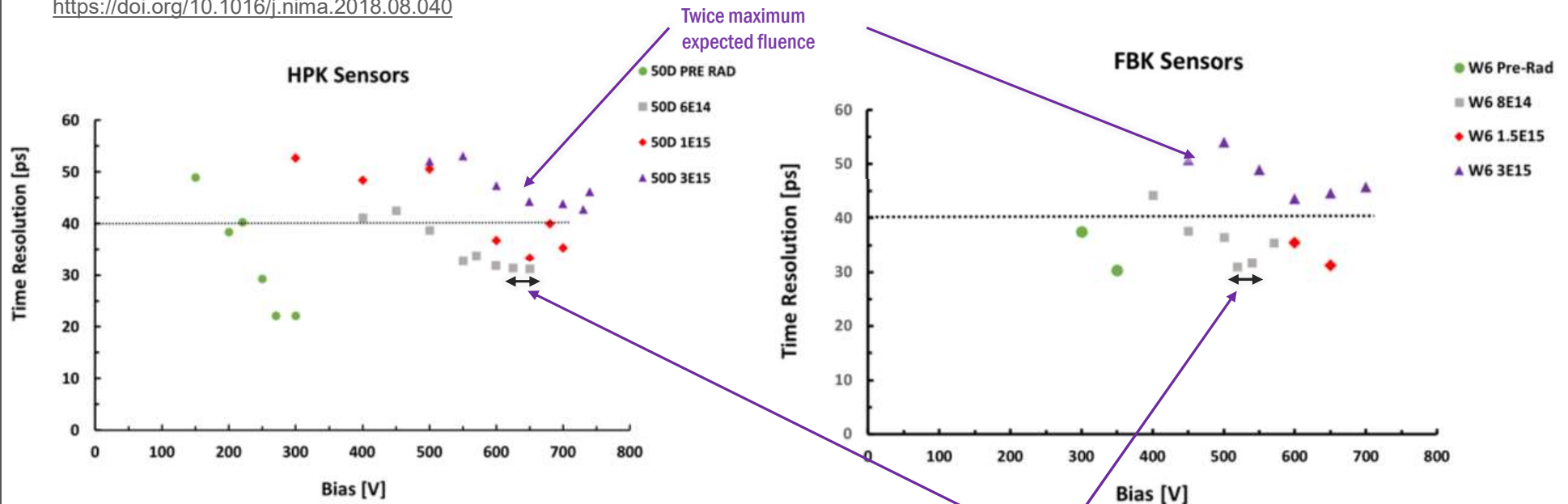
- Strong Bias increase needed to maintain $G = 10$ as a function of the irradiation level (FBK lower Bias than CNM,HPK)
- Detectors at different rapidity (radius) work at different Bias

Vendors performance ... so far

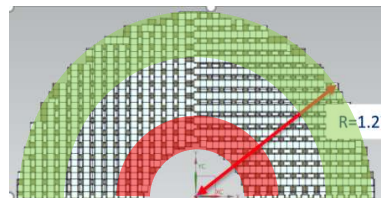


Refs:
<https://arxiv.org/abs/1804.05449v2>,
<https://arxiv.org/abs/1707.04961>,
<https://doi.org/10.1016/j.nima.2018.08.040>

Time resolution



Both HPK and FBK sensors achieve **30-35 ps** up to $1.5 \times 10^{15} n_{eq}/cm^2$ and **40-45 ps** for 2x max fluence

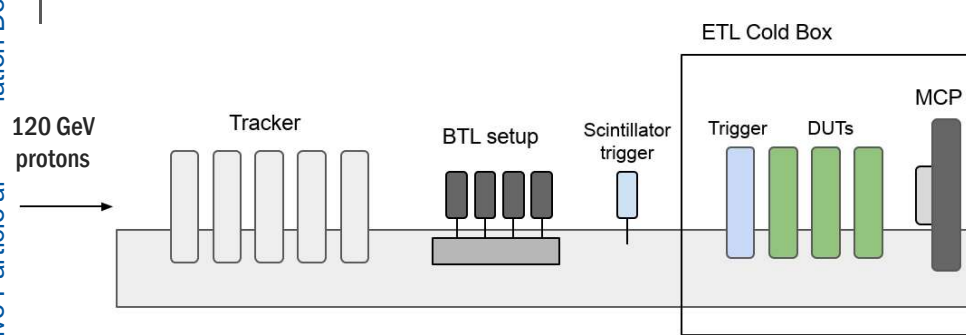


Non uniform irradiation problem mitigated: 50V “undervolt” (we expect <30V) is not significantly affecting timing performance

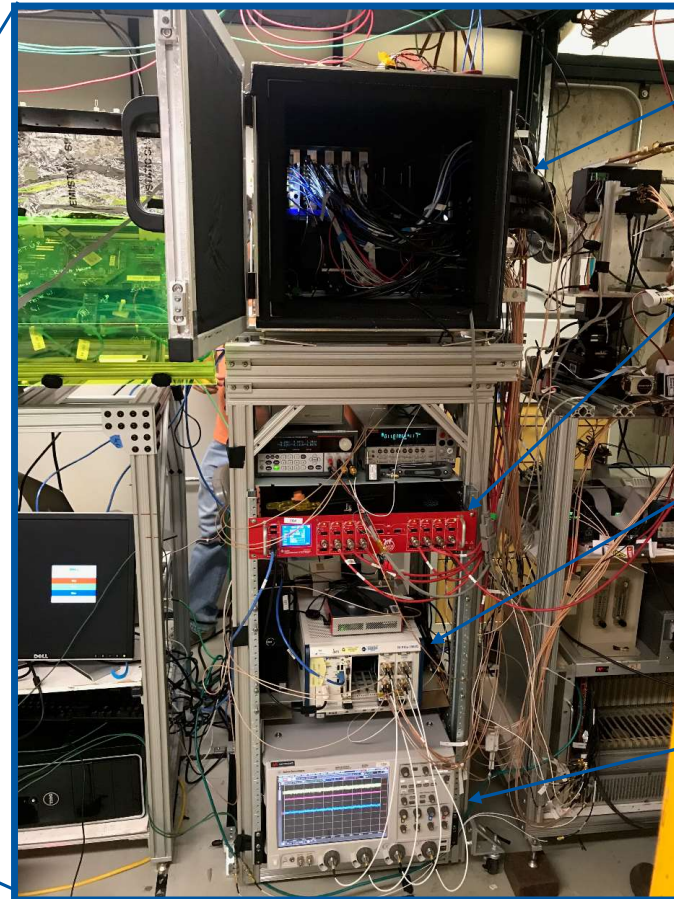
FNAL Test Beam



LGADs were tested at FNAL using an MCP-PMT as time reference and a silicon tracker to measure efficiency and uniformity



Permanent mechanical structure: ETL cold box can slide in and out of beamline as needed



Cold box (5 boards)

High Voltage

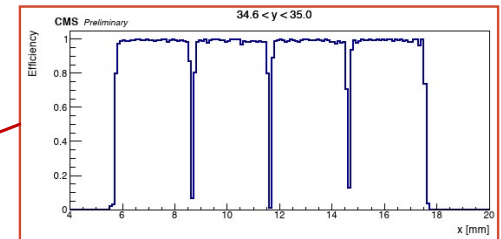
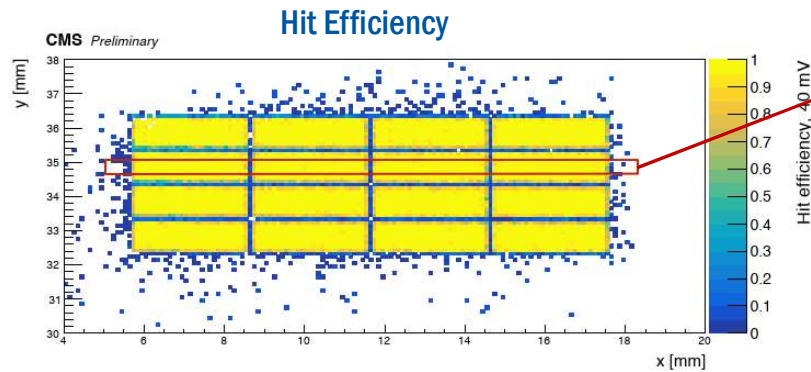
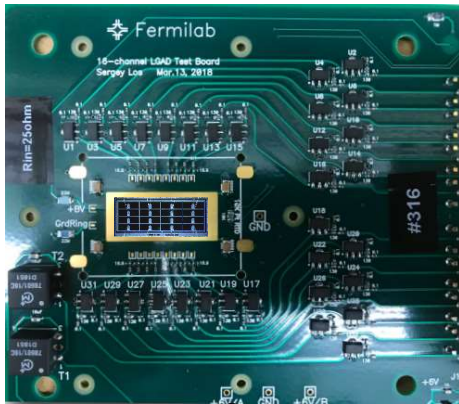
High BW multiplexer

40 Gsa/s
100k events per spill
(possibility of using Samic with 32/64 ch)

FNAL Test Beam: from single pad to arrays



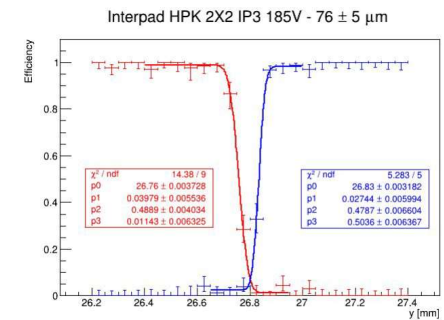
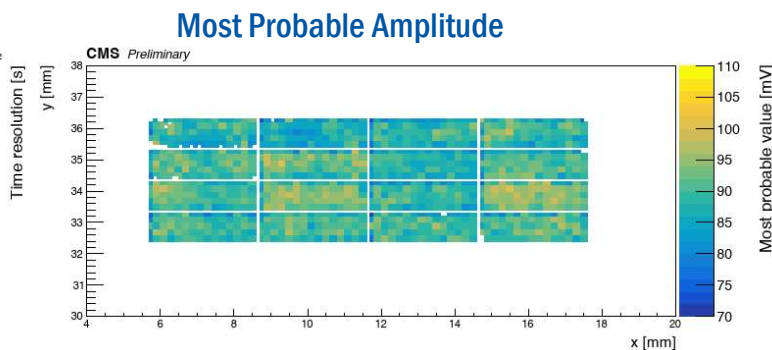
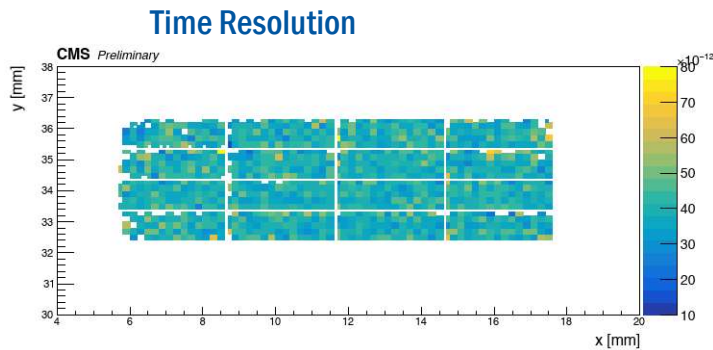
Uniformity has been studied on 16 pads arrays using a 16ch readout board



Efficiency >99% (except gaps)

Interpad distance investigated:

Fill Factor >85% per layer



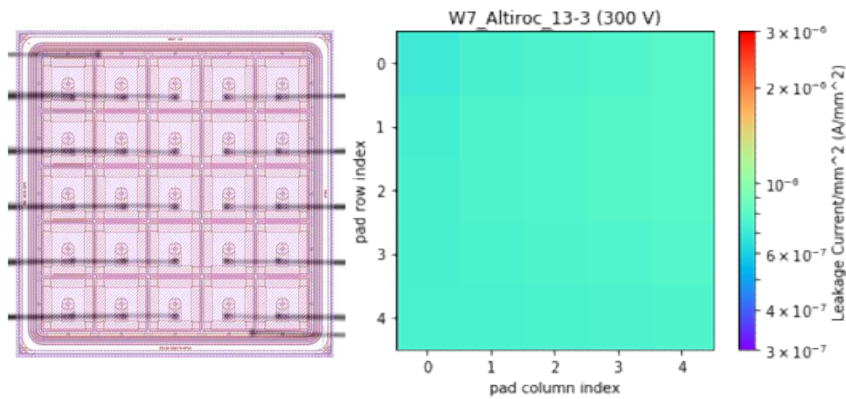
IV sensor characterization



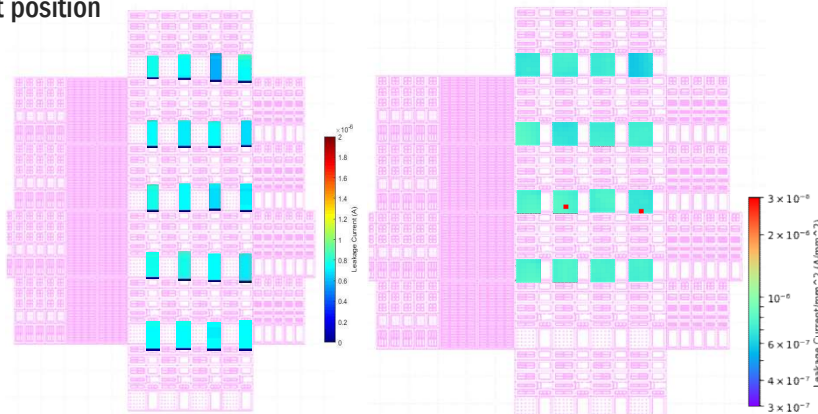
It is impossible to test several m² of sensors using a particle beam: uniformity checks using automated systems

Using a probe card it is possible to measure automatically 25 pads

All pads have a similar current @300V



Same test performed on sensors in different position on the wafer



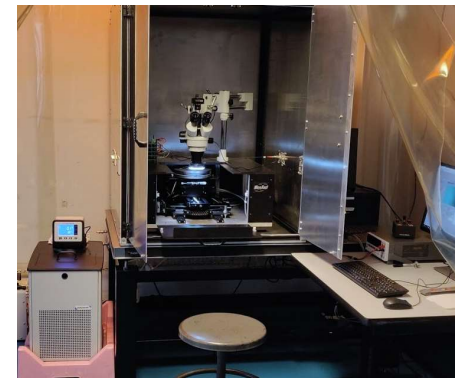
Very few channels have a leakage current away from the mode:

Table 3.4: Summary of the uniformity studies on the latest sensor productions.

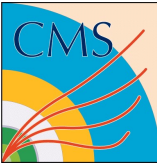
Foundries	Sensor type	# Sensors tested	# Warm pads	# Bad pads	Comments
FBK	4 × 24 pads	152	14 (0.1%)	0	bias = 100 V
FBK	5x5 pads	23	4 (0.7%)	0	bias = 300 V
HPK	4 × 24 pads	15	20 (1.3%)	0	bias = 250 V

Leakage current > 10x the mode

Leakage current too high: sensor failure

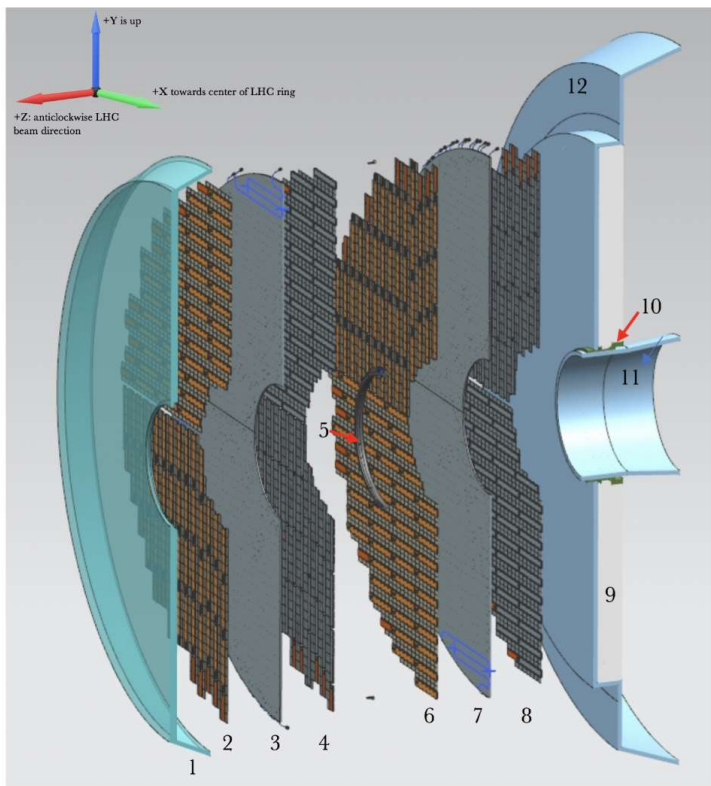


Fully automated visual checks and IV characterization of the 5-10% wafer under development



ETROC: read-out ASIC for ETL

ETROC, currently under design at FNAL, will be able to read out 16 m² of UFSDs, measuring the time of arrival with a precision better than 50 ps per hit (<30 ps per track)



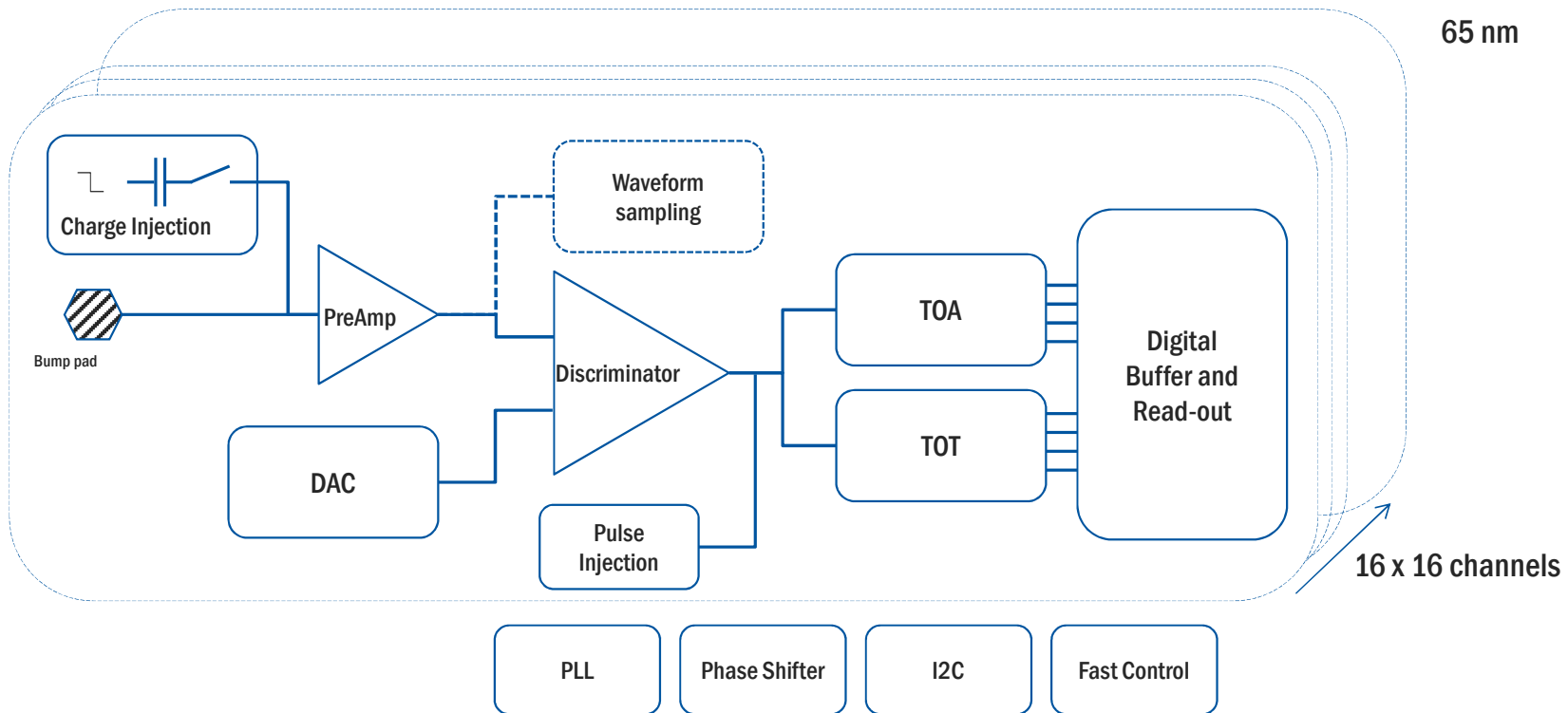
Requirements:

- < 50 ps per hit: ASIC contribution <40 ps
- Pad Size: 1.3x1.3 mm²
- Input capacitance: 3.4 pF
- MPV for MIP: ~ 6 fC for UFSD @ 10¹⁵ neq/cm²
- Buffer latency :12.5 μs
- Trigger rate: Up to 1 MHz
- Time Of Arrival: ~ 5 ns windows
- Time Over Threshold: ~ 10 ns windows
- Power consumption: <4 mW/ch (80 kW total)



ETROC0 Design

The front-end has an analog part optimized for UFSDs; 2 time to digital converters per channel; digital buffers and I&O



.... <4 mW/ch



ETROC Schedule

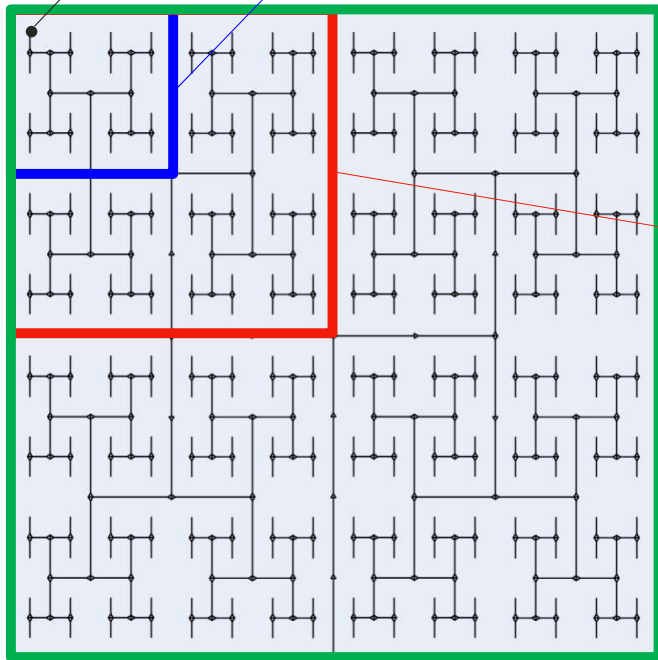
The first test is to test the analog part; to then add the TDC and finally increase the number of channels.

ETROC0: 1 channel, preamp + discriminator

ETROC1: 4x4 ch, preamp + discriminator + TDC + clock tree

Chips received and being tested

Submitted august 2019



ETROC2: 8x8 ch, fully functional (partial clock tree)

Q4 2020

ETROC3: 16x16 ch, fully functional!

Q1 2022

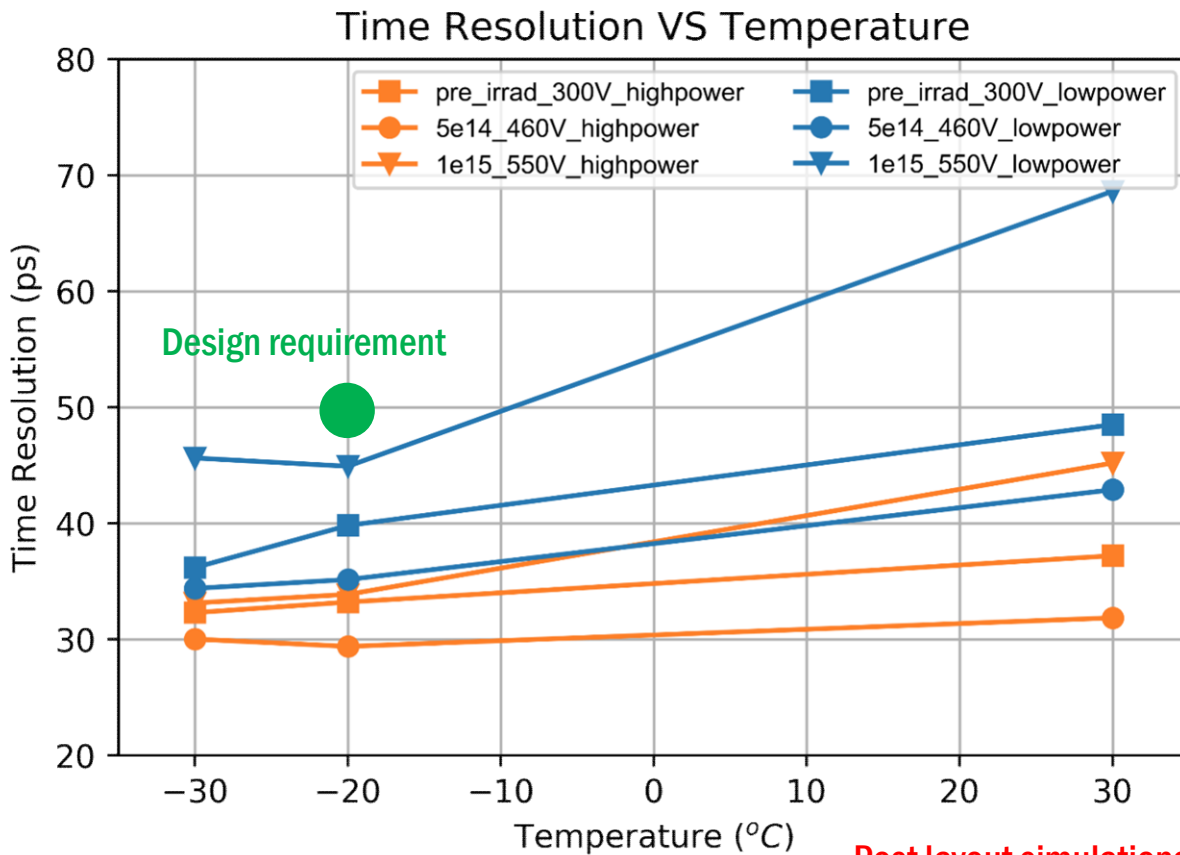
Production

Q4 2022

ETROC Preamplifier + Discriminator



The analog part of the front-end is capable of performing according to the design requirements



preamp @ **low power**:

~ 35 ps @ 5e14

preamp @ **high power**:

~ 35 ps @ 1e15

Post layout simulations: being validated with lab tests of ETROC0



ETL expected performance

The expected time resolution per track (2 hits) is expected to be better than 30 ps

$$\sigma_t^2 = \underbrace{\sigma_{sensor}^2 + \sigma_{jitter}^2 + \sigma_{digit}^2}_{\text{Sensor + preamplifier + discriminator + TDC: < 35 ps}} + \sigma_{clock}^2 + \sigma_{walk}^2 \approx 41 \text{ ps}$$

Sensor + preamplifier + discriminator + TDC: < 35 ps

Time walk correction residual: < 10 ps

Internal + system clock distributions: < 18 ps

Expected time resolution per track (2 hits): $\frac{41 \text{ ps}}{\sqrt{2}} \approx 29 \text{ ps}$

Conclusions



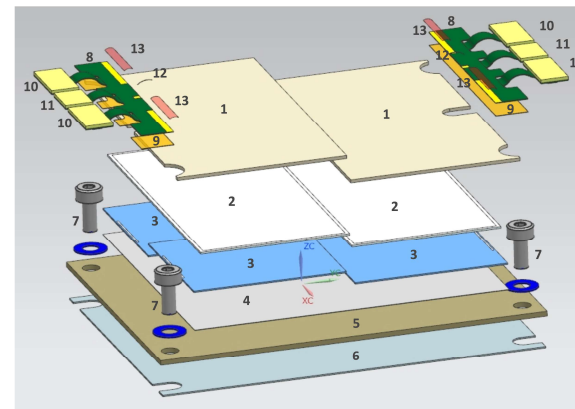
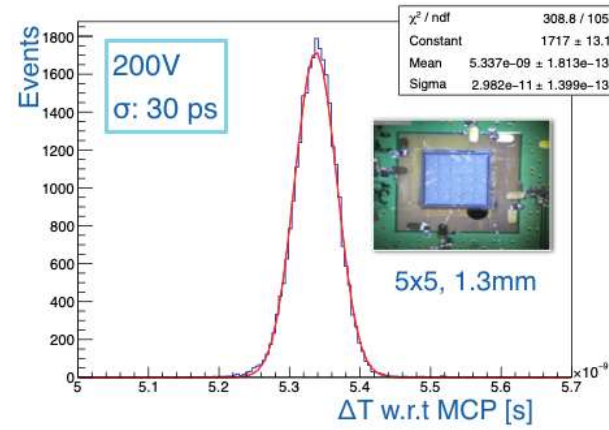
- **Sensor on schedule**

- LGAD is a mature technology
- Ultra fast silicon detector design choices nearing completion
- Received good sensors capable of satisfying ETL requirements
- <40 ps time resolution at the end of life is achievable
- Test of large arrays proved
- **Test of “very large” number of sensors under development**

- **ASIC on schedule**

- ETROC0 with analog part produced and test on going
- Good agreement with simulations
- ETROC1 submitted this summer

- **Test with sensors (on bench and with beam) planned in Q1 2020 STAY TUNED**



- 1: AlN module cover
- 2: LGAD sensor
- 3: ETL ASIC
- 4: Mounting film
- 5: AlN carrier
- 6: Mounting film
- 7: Mounting screw
- 8: Front-end hybrid
- 9: Adhesive film
- 10: Readout connector
- 11: High voltage connector
- 12: LGAD bias voltage wirebond
- 13: ETROC wirebonds



Backup

ETROC details

Summary

Table 3.5: A summary of ETROC requirements.

Requirement	Value	Comments
Process	TSMC 65 nm MS RF LP 2.5 V with metal stack 1P9M_6X1Z1U_RDL (CERN)	
Power supply	1.2 V	
Timing resolution	40 ps	Total timing resolution per hit including 30 ps contribution from sensor is 50 ps.
Pixel size	1.3×1.3 mm ²	
Pixel capacitance	3.4 pF	50 μm thickness
Pixel matrix size row x column	16 × 16	
Power consumption	below 1 W/chip	
Data storage capability	12.8 μs	Level-1 trigger latency
Trigger rate	Up to 1 MHz	
Operation temperature	−30 °C to +20 °C	
TID	100 Mrad	
SEU	TBD	system requirements

Power consumption

Table 3.7: A summary of ETROC power consumption for each circuit component. The preamplifier, discriminator, and TDC values are obtained from post-layout simulation with conservative assumptions about occupancy and operating temperature. The SRAM and global circuitry power consumptions are conservative extrapolations from similar circuits used in the ALTIROC.

Circuit component	Power per channel [mW]	Power per ASIC [mW]
Preamplifier (low-setting)	0.67	171.5
Preamplifier (high-setting)	1.25	320
Discriminator	0.71	181.8
TDC	0.2	51.2
SRAM	0.35	89.6
Supporting circuitry	0.2	51.2
Global circuitry		200
Total (low-setting)	2.13	745
Total (high-setting)	2.71	894